

**INDUSTRY STANDARD OF THE
PEOPLE'S REPUBLIC OF CHINA**

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**Measuring method for semiconductor infrared-emitting diode -
Part 15: Thermal resistance**

半导体红外发射二极管测量方法 第15部分：热阻
(English Translation)

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What this standard covers

This standard specifies the measurement principle diagram, measurement procedure and specified conditions for the thermal resistance of semiconductor infrared emitting diodes. Suitable for semiconductor infrared emitting diodes.

Document data

Chinese classification (CCS): L53.

Estimated length of the Chinese original: 6,638 words.